243 Jubug-ri, Yangji-myeon, Cheoin-gu, Yongin-si, Gyeonggi-do 449-822, Korea
Tel: +82-31-323-6008 Fax: +82-31-323-6010
http://www.ltalab.com

EMC TEST REPORT

Dates of Tests: April 22 - 27, 2019
Test Report S/N: LR500121905I
Test Site : LTA Co., Ltd.

Model No. **DC-C4212RX**

APPLICANT **IDIS CO., LTD.**

Equipment Name	:	**Network Camera**
Manufacturer	:	**IDIS CO., LTD.**
Model name	:	**DC-C4212RX**
Additional Model name	:	**NC-C4212RX, DC-C1242RX**
Test Device Serial No.:	:	**Identification**
Directive	:	**Electromagnetic Compatibility Directive 2014/30/EU**
Rule Part(s)	:	**EN 55032:2012/AC:2013**
		EN 50130-4:2011/A1:2014
Data of reissue	:	**May 03, 2019**

This test report is issued under the authority of:

Young Kyu Shin, Technical Manager

The test was supervised by:

Min gi Kang, Test Engineer

This test result only responds to the tested sample. It is not allowed to copy this report even partly without the allowance of the test laboratory. The report must not be used by the client to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.

NVLAP® TESTING NVLAP LAB CODE 200723-0

Revision	Date of issue	Test report No.	Description
0	03.05.2019	LR500121905I	Initial

TABLE OF CONTENTS

1. General information's

1-1 Test Performed

Company name	:	**LTA Co., Ltd**
Address	:	4, Songju-ro 236beon-gil, Yangji-myeon, Cheoin-gu, Yongin-si, Gyeonggi-do, 17159, Korea
Web site	:	http://www.ltalab.com
E-mail	:	chahn@ltalab.com
Telephone	:	+82-31-323-6008
Facsimile		+82-31-323-6010

Quality control in the testing laboratory is implemented as per ISO/IEC 17025 which is the "General requirements for the competents of calibration and testing laboratory".

1-2 Accredited agencies

LTA Co., Ltd. is approved to perform EMC testing by the following agencies:

Agency	Country	Accreditation No.	Validity	Reference
NVLAP	U.S.A	200723-0	2019-09-30	ECT accredited Lab.
RRA	KOREA	KR0049	-	EMC accredited Lab.
FCC	U.S.A	649054	2021-04-11	FCC CAB
VCCI	JAPAN	C-4948, T-2416, R-4483(10 m), G-10847	2020-09-10 2020-09-10 2020-10-15 2022-06-13	VCCI registration
IC	CANADA	5799A-2	2019-06-15	IC filing
KOLAS	KOREA	NO.551	2021-08-20	KOLAS accredited Lab.

2. Information's about test item

2-1 Client/ Manufacturer

Company name	:	IDIS CO., LTD.
Address	:	8-10, TECHNO 3-RO, YUSEONG-GU, DAEJEON, KOREA
Telephone / Facsimile	:	+82-31-723-5205 / +82-31-723-5108

Factory

Company name	:	IDIS CO., LTD.
Address	:	8-10, TECHNO 3-RO, YUSEONG-GU, DAEJEON, KOREA

2-2 Equipment Under Test (EUT)

Class	:	A
Equipment Name	:	Network Camera
Model name	:	DC-C4212RX
Additional Model name	:	NC-C4212RX, DC-C1242RX Additional Model is different only lens specification.
Serial number	:	Identification
Date of receipt	:	April 16, 2019
EUT condition	:	Pre-production, not damaged
Interface ports	:	LAN
Power rating	:	DC 57 V

2-3 Modification

-NONE

2-4 Test conditions

Temp. / Humid. / Pressure	:	+(21 - 24) ℃ / (36 - 41) % R.H. / (100 - 101) kPa
Tested Model	:	DC-C4212RX
Test mode	:	Capture mode
Tested Voltage	:	AC 230 V, 50 Hz

2-5 EUT

Equipment	Model No.	Serial No.	Manufacturer
Network Camera	**DC-C4212RX**	**N/A**	**IDIS CO., LTD.**

2-6 Accessary

Equipment	Model No.	Serial No.	Manufacturer
PoE Injector	SFC501G	N/A	SOL TECH
Notebook	P56	N/A	HANSUNG

2-7 Cable List

From		To		Length	Shielding	
Type	**I/O Port**	**Type**	**I/O Port**	**(m)**	**Cable**	**backshell**
EUT	LAN	POE Injector	DATA OUT	3.5	NO	Plastic
PoE Injector	DATA IN	Notebook	LAN	1.5	NO	Plastic
	AC IN	AC Power Source	3 Pin AC Line	1.2	NO	Plastic

3. Test Report

3.1 Summary of tests

Parameter	Applied Standard	Status
I. Emission		
Radiated Emission	EN 55032:2012/AC:2013	C
Conducted Emission	EN 55032:2012/AC:2013	C
Harmonic Current Emission	EN 61000-3-2:2014	N/A Note3
Voltage Fluctuations and Flicker	EN 61000-3-3:2013	NA
II. Immunity		
Electrostatic Discharge	EN 61000-4-2:2009	C
RF Electromagnetic field	EN 61000-4-3:2006/A1:2008/A2:2010	C
Fast Transients Common mode	EN 61000-4-4:2012	C
Surges, line to line and line to ground	EN 61000-4-5:2014/A1:2017	NA
RF common mode	EN 61000-4-6:2014/AC:2015	C
Voltage dips and Interruptions	EN 61000-4-11:2004/A1:2017	NA
Main supply voltage variations	EN 50130-4:2011/A1:2014	NA

Note 1: C=Complies NC=Not Complies NT=Not Tested NA=Not Applicable

Note 2: The data in this test report are traceable to the national or international standards.

Note 3: We did not test EN61000-3-2 (Harmonic current emissions) for the DC-C4212RX because equipment whose rated power is DC 57 V don't need to be tested.

3.2 EMISSION

3.2.1 Conducted emissions

Definition:

The test assesses the ability of the EUT to limit its internal noise from being present on the AC mains Power In/Output ports.

We were performed the test according to LTA procedure LTA-QI-04.

Measurement Frequency range	:	150 kHz – 30 MHz
Test method	:	EN 55032:2012/AC:2013
Measurement RBW	:	9 kHz
Test mode	:	Capture mode
Result	:	**Complies**

Measurement Data:

- Refer to the Next page (Maximum emission configuration)

A sample calculation:

COR. F (correction factor)= LISN Insertion loss + Cable loss + Pulse Limiter Factors

Emission Level= meter reading + COR.F

Limits for conducted disturbance at the mains ports of class A ITE

Frequency Range	Quasi-peak	Average
(0.15 – 0.5) MHz	79 dBuV	66 dBuV
(0.5 – 30) MHz	73 dBuV	60 dBuV
Note: The limits will decrease with the frequency logarithmically within 0.15MHz to 0.5MHz		

Limits for conducted disturbance at the mains ports of class B ITE

Frequency Range	Quasi-peak	Average
(0.15 – 0.5) MHz	(66 – 56) dBuV	(56 - 46) dBuV
(0.5 – 5) MHz	56 dBuV	46 dBuV
(5 – 30) MHz	60 dBuV	50 dBuV
Note: The limits will decrease with the frequency logarithmically within 0.15 MHz to 0.5 MHz		

Limits of conducted common mode (asymmetric mode) disturbance at telecommunication ports in the frequency range 0.15 MHz to 30 MHz for class A equipment

Frequency Range	Voltage limits		Current limits	
	Quasi-peak	Average	Quasi-peak	Average
(0.15 – 0.5) MHz	(97 − 87) dBuV	(84 − 74) dBuV	(53 − 43) dBuV	(40 − 30) dBuV
(0.5 – 30) MHz	87 dBuV	74 dBuV	43 dBuV	30 dBuV

Note 1: The limits decrease linearly with the logarithm of the frequency in the range 0.15 MHz to 0.5 MHz.

Note 2: The current and voltage disturbance limits are derived for use with an impedance stabilization network (ISN) which presents a common mode (asymmetric mode) impedance of 150Ω to the telecommunication port under test (conversion factor is 20 $\log_{10}$ 150/I= 44 dB)

Limits of conducted common mode (asymmetric mode) disturbance at telecommunication ports in the frequency range 0.15 MHz to 30 MHz for class B equipment

Frequency Range	Voltage limits		Current limits	
	Quasi-peak	Average	Quasi-peak	Average
(0.15 – 0.5) MHz	(84 − 74) dBuV	(74 − 64) dBuV	(40 − 30) dBuV	(30 − 20) dBuV
(0.5 – 30) MHz	74 dBuV	64 dBuV	30 dBuV	20 dBuV

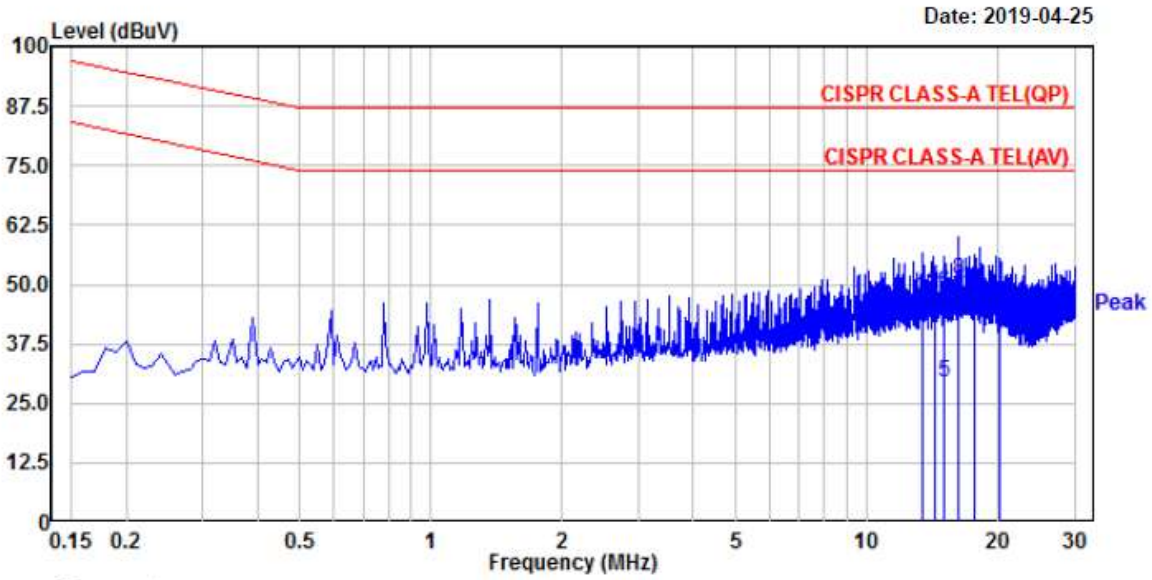
Note 1: The limits decrease linearly with the logarithm of the frequency in the range 0.15 MHz to 0.5 MHz.

Note 2: The current and voltage disturbance limits are derived for use with an impedance stabilization network (ISN) which presents a common mode (asymmetric mode) impedance of 150Ω to the telecommunication port under test (conversion factor is 20 $\log_{10}$ 150/I= 44 dB)

Conducted emissions (TEL_100 M)

4, Songjuro 236 Beon-gil, Yangji-myeon
Cheoin-gu, Youngin-si, Gyeonggi-do
449-822 Korea
Tel:+82-31-3236008,9
Fax:+82-31-3236010

EUT /Model No.	: DC-C4212RX	Phase	: TEL 100M
Test Mode	: Capture mode	Test Power	: 230 / 50
Temp./ Humi.	: 24'C / 41% R.H.	Test Engineer	: KANG M G



Trace: 1

Freq	RD QP	RD AV	C.F	Result QP	Result AV	Limit QP	Limit AV	Margin QP	Margin AV
MHz	dBuV	dBuV	dB	dBuV	dBuV	dBuV	dBuV	dB	dB
13.358	26.96	25.57	19.68	46.64	45.25	87.00	74.00	40.36	28.75
14.273	29.86	25.97	19.71	49.57	45.68	87.00	74.00	37.43	28.32
15.021	28.78	9.89	19.71	48.49	29.60	87.00	74.00	38.51	44.40
16.227	31.14	27.56	19.76	50.90	47.32	87.00	74.00	36.10	26.68
17.694	24.57	23.14	19.80	44.37	42.94	87.00	74.00	42.63	31.06
20.140	24.63	20.85	19.87	44.50	40.72	87.00	74.00	42.50	33.28

Remarks: C.F (Correction Factor) = Insertion loss + Cable loss + Pulse Limiter

3.2.2 Radiated Emission

Definition:

The test assesses the ability of ancillary equipment to limit their internal noise from being radiated from the enclosure.

We were performed the test according to LTA procedure LTA-QI-04.

Test method	:	EN 55032:2012/AC:2013
Measuring Distance	:	10 m for below 1 GHz / 3 m for above 1 GHz
Measurement Frequency range	:	30 MHz – 6 000 MHz
Measurement RBW	:	120 kHz @ 10 m / 1 MHz @ 3 m
Test mode	:	Capture mode
Result	:	**Complies**

Measurement Data:

- Refer to the Next page (Maximum emission configuration)

- The highest internal source of an EUT is higher than 108 MHz, the measurement shall be made up to 6 GHz.

(The highest internal source of an EUT : 594 MHz)

A sample calculation:

COR. F (correction factor)= Antenna factor + Cable loss- Amp.gain- Distance correction

Emission Level= meter reading + COR.F

Limit of 10 m for below 1 GHz

CLASS A

Frequency Range	Quasi-peak
(30 – 230) MHz	40 dBuV/m
(230 – 1 000) MHz	47 dBuV/m

CLASS B

Frequency Range	Quasi-peak
(30 – 230) MHz	30 dBuV/m
(230 – 1 000) MHz	37 dBuV/m

Limit of 3m for above 1 GHz

CLASS A

Frequency Range	Average Limit @ 3m (dBμV/m)	Peak limit @ 3m (dBμV/m)
(1 000 – 3 000) MHz	56	76
(3 000 – 6 000) MHz	60	80
NOTE:	The lower limit applies at the transition frequency.	

CLASS B

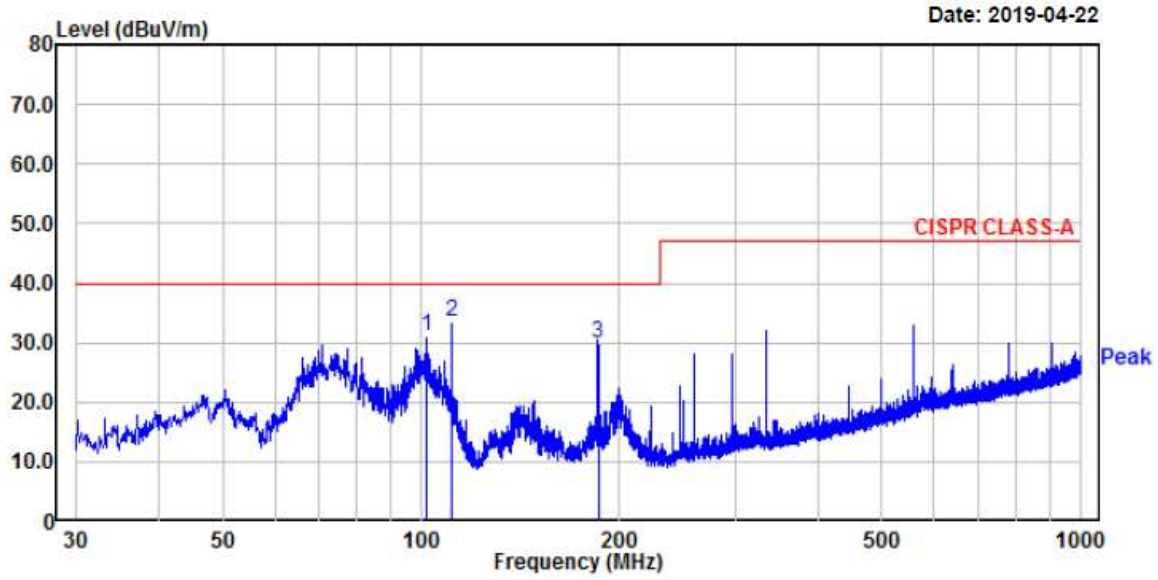
Frequency Range	Average Limit @ 3m (dBμV/m)	Peak limit @ 3m (dBμV/m)
(1 000 – 3 000) MHz	50	70
(3 000 – 6 000) MHz	54	74
NOTE:	The lower limit applies at the transition frequency.	

Radiated Emission (Below 1 GHz)

4, Songjuro 236Beon-gil, yanggi-myeon,
Yongin-si, Gyeonggi-do, Korea
Tel : +82-31-3236008,9
Fax : +82-31-3236010
www.ltalab.com

EUT/Model No.: DC-C4212RX Temp/Humi: 23 / 36

Test Mode : Capture mode Tested by: KANG M G



Freq	Reading	C.F	Result QP	Limit	Margin	Height	Angle	Polarity
MHz	dBuV	dB	dBuV/m	dBuV/m	dB	cm	deg	
101.87	48.39	-17.20	31.19	40.00	8.81	146	304	vertical
111.37	49.17	-15.80	33.37	40.00	6.63	150	107	vertical
185.63	44.23	-14.34	29.89	40.00	10.11	100	325	vertical

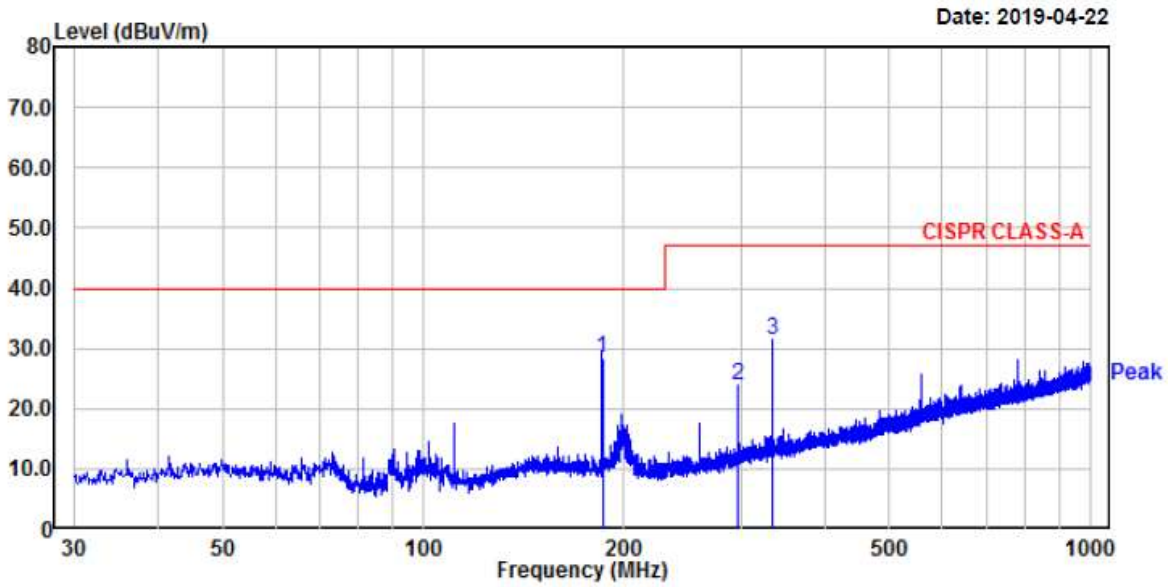
Remarks: C.F (Correction Factor) = Antenna factor + Cable loss - Preamp gain

Radiated Emission (Below 1 GHz)

4, Songjuro 236Beon-gil, yanggi-myeon,
Yongin-si, Gyeonggi-do, Korea
Tel : +82-31-3236008,9
Fax : +82-31-3236010
www.ltalab.com

EUT/Model No.: DC-C4212RX Temp/Humi: 23 / 36

Test Mode : Capture mode Tested by: KANG M G



Freq	Reading	C.F	Result QP	Limit	Margin	Height	Angle	Polarity
MHz	dBuV	dB	dBuV/m	dBuV/m	dB	cm	deg	
185.62	42.73	-14.34	28.39	40.00	11.61	330	312	horizontal
297.00	34.78	-11.07	23.71	47.00	23.29	320	293	horizontal
334.13	41.38	-10.07	31.31	47.00	15.69	310	288	horizontal

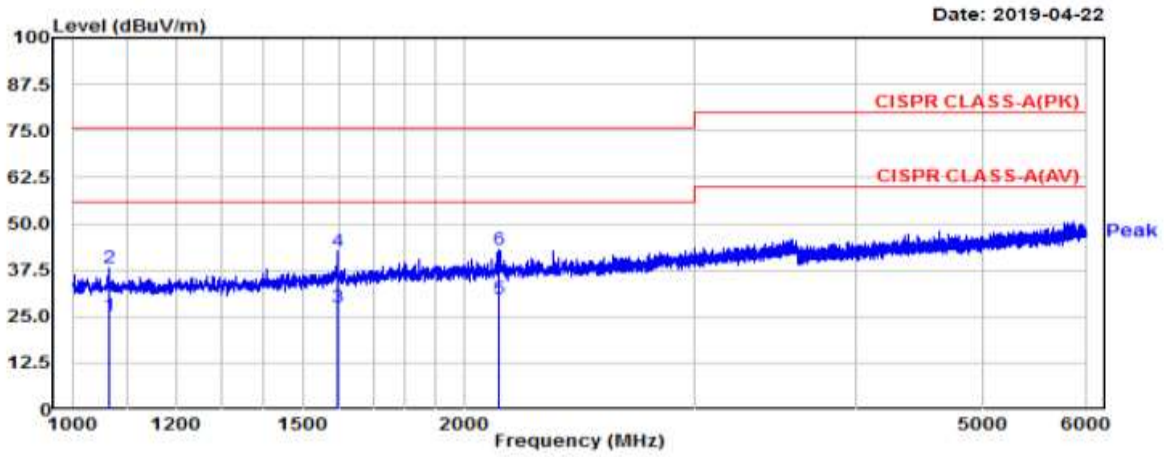
Remarks: C.F (Correction Factor) = Antenna factor + Cable loss - Preamp gain

Radiated Emission (Above 1 GHz)

(Above 1 GHz) / V

EUT/Model No.: DC-C4212RX Temp/Humi: 23 / 36

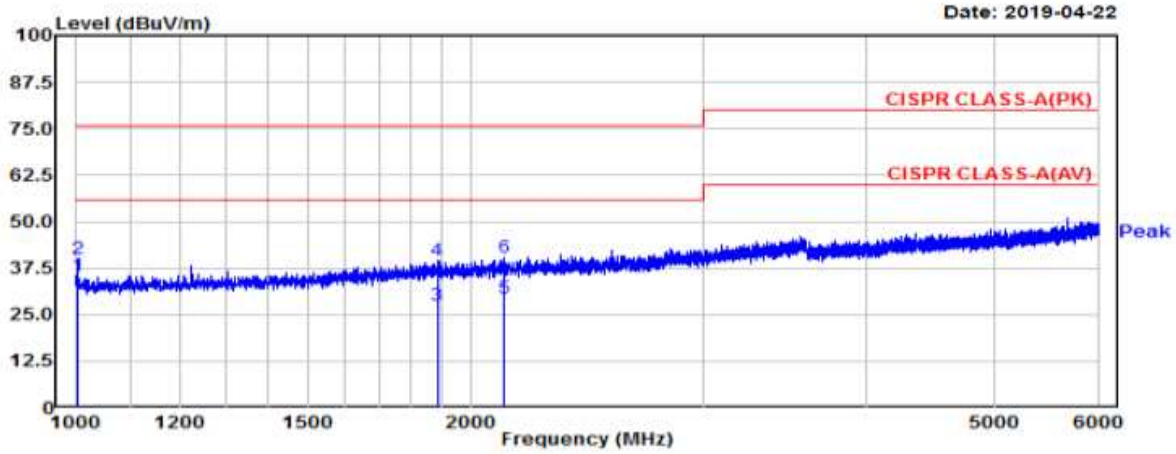
Test Mode : Capture mode Tested by: KANG M G



(Above 1 GHz) / H

EUT/Model No.: DC-C4212RX Temp/Humi: 23 / 36

Test Mode : Capture mode Tested by: KANG M G



Manufacture : IDIS CO., LTD.
Model : DC-C4212RX
TEST mode : Capture mode

Test Date	Temp.: [℃]	Humidity : [%]	Distance (m)
2019-04-22	23	36	4.1

Freq.(MHz)	Reading(PK)	Reading(AV)	C.F	Result(PK)	Result(AV)	Limit(PK)	Limit(AV)	Margin(PK)	Margin(AV)	Height	Angle	Polarity
MHz	dBuV	dBuV	dB	dBuV/m	dBuV/m	dBuV/m	dBuV/m	dB	dB	cm	deg	Hor/Ver
1001.9	50.2	45.7	-7.5	42.70	38.22	76.0	56.0	33.30	17.78	100	144	H
1883.1	43.3	31.4	-1	42.28	30.41	76.0	56.0	33.72	25.59	100	357	H
2115.6	41.7	30.6	1.55	43.25	32.13	76.0	56.0	32.75	23.87	100	96	H
1065.0	47.8	34.9	-6.95	40.83	27.96	76.0	56.0	35.17	28.04	100	340	V
1595.6	48.4	33.5	-3.1	45.25	30.40	76.0	56.0	30.75	25.60	100	220	V
2124.4	45.0	31.5	0.85	45.80	32.36	76.0	56.0	30.20	23.64	100	2	V

3.3 IMMUNITY

3.3.1 Electrostatic Discharge

Definition:

The test assesses the ability of the EUT to operate as intended in the event of an electrostatic discharge.
We were performed the test according to LTA procedure LTA-QI-04.

Test date	:	2019.04.26.
Test method	:	EN 61000-4-2 :2009
Temperature / Humidity / Pressure	:	22 ℃ / 41 % R.H. / 100 kPa
Discharge Impedance	:	(330 ±10%)Ω / (150 ±10%) pF
Type of Discharge (air discharge)	:	± 2kV, ± 4 kV, ± 8 kV
Type of Discharge (contact discharge)	:	± 6 kV
Number of discharges at each point	:	10 of each polarity
Discharge Repetition on Rate	:	1 / sec
Test mode	:	Capture mode
Result	:	**Complies**

Measurement Data:

1-1. Indirect Discharge

No.	Position	Kind of Discharge	Results	Remarks
1	HCP	Contact	Complies	No reaction recognized
2	VCP	Contact	Complies	No reaction recognized

1-2. Direct Discharge

No.	Position	Kind of Discharge	Result	Remarks
1	Enclosure	Air	Complies	No reaction recognized
2	Lens	Air	Complies	No reaction recognized

Air discharge

Contact discharge

ESD TEST POINT

3.3.2 RF Electromagnetic Field

Definition:

The test assesses the ability of the EUT to operate as intended in the presence of a radio frequency electromagnetic field disturbance.

We were performed the test according to LTA procedure LTA-QI-04.

Test date	:	2019.04.27.
Test method	:	EN 61000-4-3:2006/A1:2008/A2:2010
Temperature / Humidity / Pressure	:	22 ℃ / 38 % R.H. / 101 kPa
Frequency range	:	80 ㎒ to 2,700 ㎒
Test level	:	10 V/m (measured unmodulated)
Amplitude Modulation	:	AM, 80 %, 1 ㎑ Sinusoidal
		PM, 1 ㎐ (0.5s ON : 0.5s OFF)
Step size	:	1 % of fundamental
Dwell Time	:	3 s
Test mode	:	Capture mode
Result	:	**Complies**

Measurement Data:

Port	Side	Result	Remarks
Horizontal	Front	Complies	No reaction recognized
	Left	Complies	No reaction recognized
	Rear	Complies	No reaction recognized
	Right	Complies	No reaction recognized
Vertical	Front	Complies	No reaction recognized
	Left	Complies	No reaction recognized
	Rear	Complies	No reaction recognized
	Right	Complies	No reaction recognized

3.3.3 Electrical fast transients

Definition:

The test assesses the ability of the EUT to operate as intended in the event of fast transients presence on one of the input/output ports.

We were performed the test according to LTA procedure LTA-QI-04.

Test date	:	2019.04.26.
Test method	:	EN 61000-4-4:2012
Temperature / Humidity / Pressure	:	22 ℃ / 42 % R.H. / 100 kPa
Cable length	:	> 3 m
Test level	:	2.0 kV (AC power input port)
		1.0 kV (Signal port)
Polarity	:	Negative/ positive
Repetition frequency	:	100 ㎑
Test mode	:	Capture mode
Result	:	**Complies**

Measurement Data:

Signal Line	Test level	Result	Remarks
LAN	± 1 kV	Complies	No reaction recognized

3.3.4 Conducted disturbances, induced by radio-frequency fields

Definition:

The test assesses the ability of the EUT to operate as intended in the presence of a radio frequency electromagnetic disturbance on the input/output ports.

We were performed the test according to LTA procedure LTA-QI-04.

Test date	:	2019.04.26.
Test method	:	EN 61000-4-6:2014/AC:2015
Temperature / Humidity / Pressure	:	21 ℃ / 40 % R.H. / 100 kPa
Frequency range	:	0.15㎒ – 100 ㎒
Test level	:	10 Vrms unmodulated
Amplitude Modulation	:	AM, 80 %, 1 ㎑ Sinusoidal
		PM, 1 ㎐ (0.5s ON : 0.5s OFF)
Step size	:	1 % of fundamental.
Test mode	:	Capture mode
Result	:	**Complies**

Measurement Data:

Power Port	Test level (Vrms)	Result	Remarks
LAN	10	Complies	No reaction recognized

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APPENDIX A

TEST EQUIPMENT AND ANCILLARIES USED FOR TESTS

To facilitate inclusion on each page of the test equipment used for related tests, each item of test equipment are identified by the Test Laboratory.

Conducted emissions

	Item	Model Name	Manufacturer	Serial No.	Next Cal.	Interval
☒	EMI TEST Receiver	ESR	Rohde & Schwarz	101499	2019.07.11	1 year
☒	Pulse Limiter	ESH3-Z2	Rohde & Schwarz	100710	2020.03.16	1 year
☒	ISN	ISN T800	TESEQ	27109	2019.09.12	1 year
☐	ISN	ENY81-CA6	Rohde & Schwarz	101565	2019.09.12	1 year
☐	CURRENT PROBE	EZ-17	Rohde & Schwarz	100508	2019.09.06	1 year
☐	LISN	ESH3-Z6	Rohde & Schwarz	100378	2019.09.07	1 year
☐	LISN	ESH3-Z6	Rohde & Schwarz	101468	2019.09.07	-
☒	LISN(main)	ENV216	Rohde & Schwarz	100408	2019.10.10	1 year
☒	LISN(sub)	LT32C/10	AFJ	32031518210	2019.09.06	1 year
☒	TEST PROGRAM	e3_ce 20181212a (V9)	AUDIX	-	-	1 year

Radiated Emission – Below 1 GHz

	Item	Model Name	Manufacturer	Serial No.	Next Cal.	Interval
☒	EMI TEST Receiver	ESU	Rohde & Schwarz	100092	2019.09.06	1 year
☒	Amplifier (25 ㏈)	8447D	HP	2944A07684	2019.09.06	1 year
☒	BILOG Antenna	VULB9168	SCHWARZBECK	775	2020.03.16 (KOLAS)	2 year
☒	TEST PROGRAM	e3 20181212a (V9)	AUDIX	-	-	-

Radiated Emission – Above 1 GHz

	Item	Model Name	Manufacturer	Serial No.	Next Cal.	Interval
☒	EMI TEST Receiver	ESU	Rohde & Schwarz	100092	2019.09.06	1 year
☒	Amplifier	8449B	HP	3008A00671	2019.09.06	1 year
☒	HORN ANTENNA	3115	ETS	114105	2019.11.03 (KOLAS)	2 year
☒	TEST PROGRAM	e3 20181212a (V9)	AUDIX	-	-	-

Electrostatic Discharge

	Item	Model Name	Manufacturer	Serial No.	Next Cal.	Interval
☒	ESD Simulator	ESS-2000	NOISEKEN	8000C03241	2019.09.11	1 year
☒	ESD GUN	TC-815R	NOISEKEN	ESS0564361	2019.09.11	1 year

RF Electromagnetic Field

	Item	Model Name	Manufacturer	Serial No.	Next Cal.	Interval
☒	Signal Generator	E4432B	Agilent	MY41310632	2020.03.16	1 year
☒	Power Meter	E4419B	Agilent	GB38410133	2020.03.16	1 year
☒	Power Sensor	E9300A	Agilent	MY41497992	2020.03.16	1 year
☒	Power Sensor	E9300A	Agilent	MY41497618	2020.03.16	1 year
☒	RF POWER AMPLIFIER	ITA0300KL-300	INFINITECH	0300KL 1507 001	-	-
☒	RF POWER AMPLIFIER	ITA2000KL-120	INFINITECH	200KL 1507 001	-	-
☒	RF POWER AMPLIFIER	ITA4500KL-70	INFINITECH	4500KL 1507 001	-	-
☒	RF POWER AMPLIFIER	ITA0750KL-300	INFINITECH	0750KL 1507 001	-	-
☒	Log.-Per.Antenna (80 ㎒ ~ 3 ㎓)	K9128	RAPA	NONE	-	-

Electrical fast transients

	Item	**Model Name**	**Manufacturer**	**Serial No.**	**Next Cal.**	**Interval**
☒	Compact Generator	Compact NX	EMTEST	P1725200196	2019.09.06	1 year
☒	AC Power Source	Variac NX	EMTEST	P1745207276	2019.09.06	1 year
☒	Capacitive Coupling Clamp	CCI	EMTEST	P1744207071	2019.09.06	1 year

Conducted disturbances, induced by radio-frequency fields

	Item	Model Name	Manufacturer	Serial No.	Next Cal.	Interval
☒	Signal generator	SML03	R&S	103026/0013	2020.03.16	1 year
☒	POWER METER	NRVD	R&S	101689	2020.03.16	1 year
☒	POWER Sensor	URV5-Z2	R&S	100755	2020.03.16	1 year
☒	POWER Sensor	URV5-Z2	R&S	100756	2020.03.16	1 year
☒	RF Power Amplifier	FLL75A	FRANKONIA	1033	-	-
☒	EM INJECTION CLAMP	TSIC-23	F.C.C	529	2020.03.25	1 year
☐	CDN (M1)	TSCDN-M1-16A	F.C.C	07004	2020.03.16	1 year
☐	CDN (M2)	TSCDN-M2-16A	F.C.C	07008	2019.09.06	1 year
☐	CDN (M2)	TSCDN-M2-16A	F.C.C	07009	2020.03.16	1 year
☒	CDN (M3) (main)	TSCDN-M3-16A	F.C.C	07016	2020.03.16	1 year
☒	CDN (M3) (sub)	TSCDN-M3-16A	F.C.C	07017	2019.09.06	1 year

APPENDIX B

PERFORMANCE CRITERIA

Performance criteria

The variety and the diversity of the apparatus within the scope of this document makes it difficult to define precise criteria for the evaluation of the immunity test results.
If as a result of the application of the tests defined in this standard, the apparatus becomes dangerous or unsafe then the apparatus shall be deemed to have failed the test.
A functional description and a definition of performance by the manufacture and noted in the test report, based on the following criteria:

Electrostatic discharge

There shall be no damage, malfunction or change of status due to the conditioning.
Flickering of an indicator during the application of discharge is permissible, providing that there is no residual change in the EUT or any change in outputs, which could be interpreted by associated equipment as a change. The EUT shall meet the acceptance criteria for the functional test
(see Clause 6), after the conditioning.

Radiated electromagnetic fields

There shall be no damage, malfunction or change of status due to the conditioning.
Flickering of an indicator during the conditioning is permissible, providing that there is no residual change in the EUT or any change in outputs, which could be interpreted by associated equipment as a change, and no such flickering of indicators occurs at a field strength of 3 V/m.
For components of CCTV systems, where the status is monitored by observing the TV picture, then deterioration of the picture is allowed at 10 V/m, providing.
(a) there is no permanent damage or change to the EUT
(e.g. no corruption of memory or changes to programmable setting etc.)
(b) at 3 V/m, any deterioration of the picture is so minor that the system could still be used; and
(c) there is no observable deterioration of the picture at 1 V/m.
The EUT shall meet the acceptance criteria for the functional test(see Clause 6), after the conditioning.

Fast transient burst / slow high energy voltage surge

There shall be no damage, malfunction or change of status due to the conditioning.
Flickering of an indicator during the application of the bursts is permissible, providing that there is no residual change in the EUT or any change in outputs, which could be interpreted by associated equipment as a change. The EUT shall meet the acceptance criteria for the functional test
(see Clause 6), after the conditioning.

Slow high energy voltage surge

There shall be no damage, malfunction or change of status due to the conditioning.
Flickering of an indicator during the application of the surges is permissible, providing that there is no residual change in the EUT or any change in outputs, which could be interpreted by associated equipment as a change. The EUT shall meet the acceptance criteria for the functional test
(see Clause 6), after the conditioning.

Conducted RF immunity

There shall be no damage, malfunction or change of status due to the conditioning.
Flickering of an indicator during the conditioning is permissible, providing that there is no residual change in the EUT or any change in outputs, which could be interpreted by associated equipment as a change, and no such flickering of indicators occurs at U0 = 130 dBμV.
For components of CCTV systems, where the status is monitored by observing the TV picture, then deterioration of the picture is allowed at U0 = 140 dBμV, providing
(a) there is no permanent damage or change to the EUT
(e.g. no corruption of memory or changes to programmable settings, etc.)
(b) at U0 = 130 dBμV, any deterioration of the picture is so minor that the system could still be used, and
(c) there is no observable deterioration of the picture at U0 = 120 dBμV.
The EUT shall meet the acceptance criteria for the functional test(see Clause 6), after the conditioning.

Voltage dip/interruption

There shall be no damage, malfunction or change of status due to the conditioning.
Flickering of an indicator during the conditioning is permissible, providing that there is no residual change in the EUT or any change in outputs, which could be interpreted by associated equipment as a change. The EUT shall meet the acceptance criteria for the functional test(see Clause 6), after the conditioning.
It is permitted to use ancillary equipment (e.g. A UPS) to meet the requirements of this clause. This shall be detailed in the test report and the manufacturer's installation manual.
Signaling a mains fault during the 100 % voltage reduction test is permitted.

Mains supply voltage variations

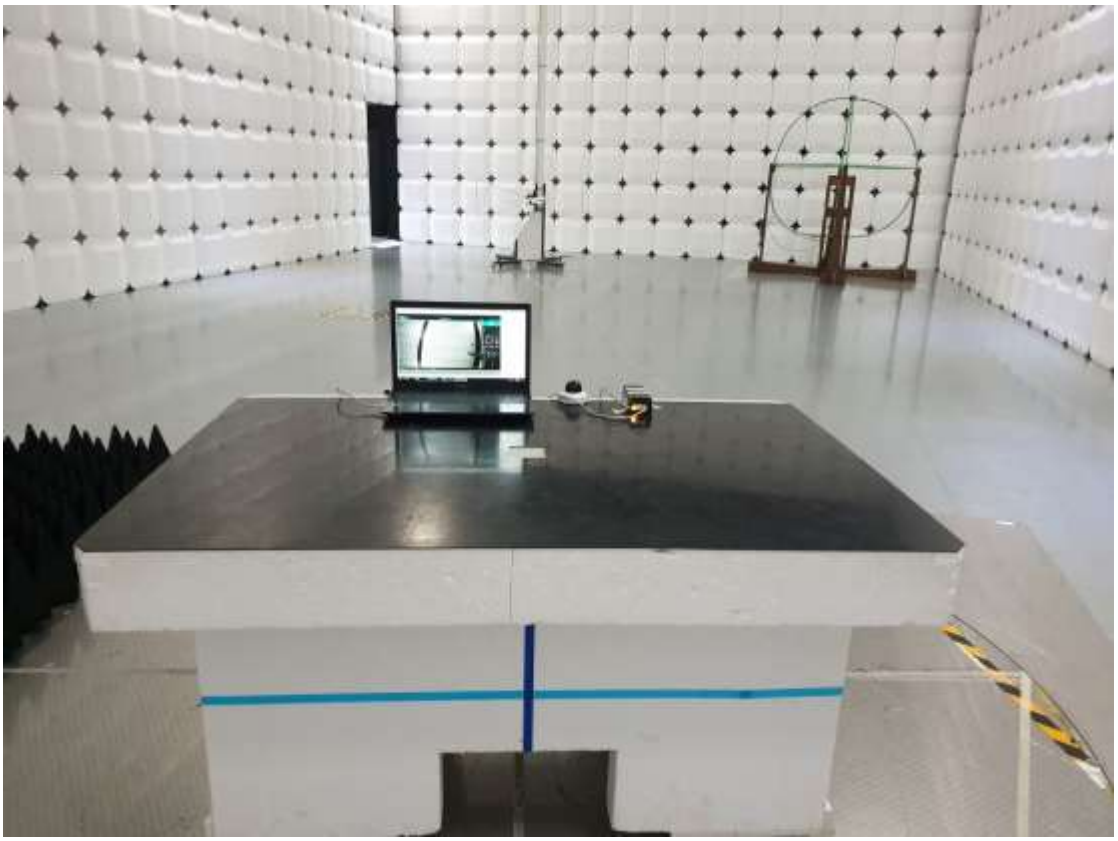
There shall be no damage, malfunction or change of status due to the different supply voltage conditions. The EUT shall meet the acceptance criteria for the functional test(see Clause 6), during the conditioning.

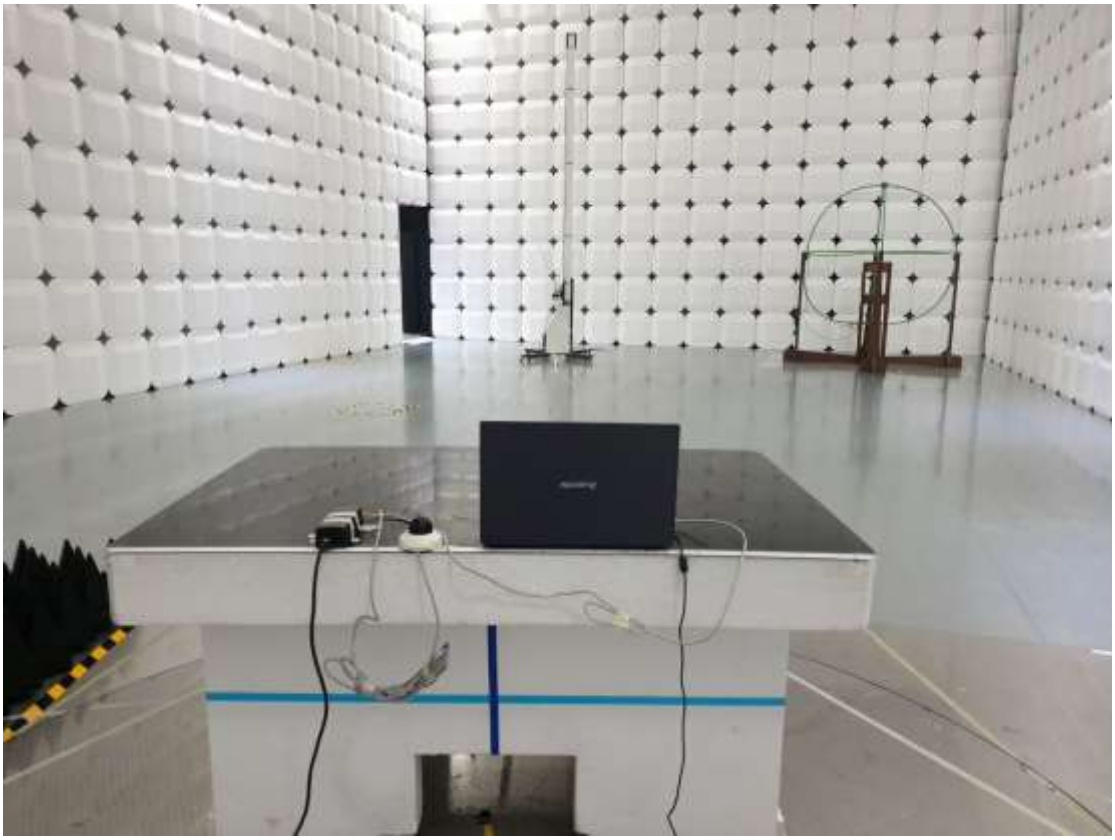
APPENDIX C

PHOTOGRAPHS

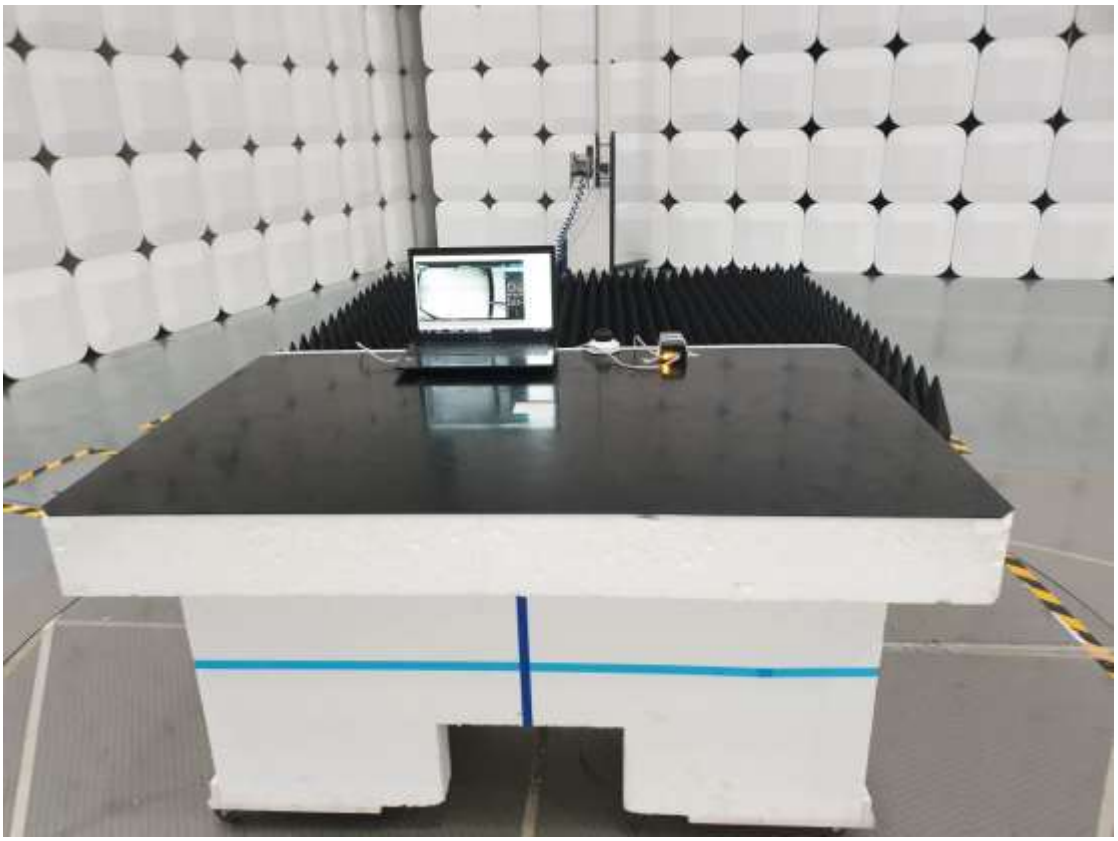
Conducted emission (Maximum emission configuration) / TEL

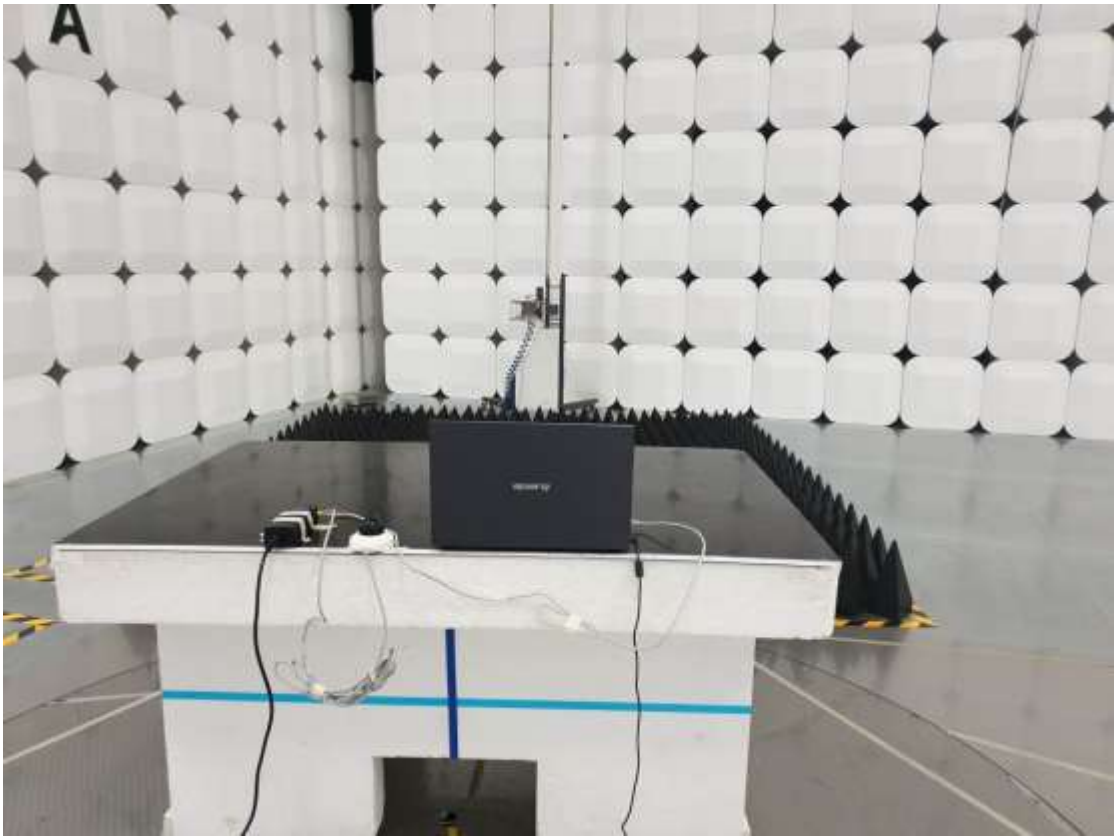
Radiated emission (Maximum emission configuration)-Below 1 GHz





Radiated emission (Maximum emission configuration) – Above 1GHz

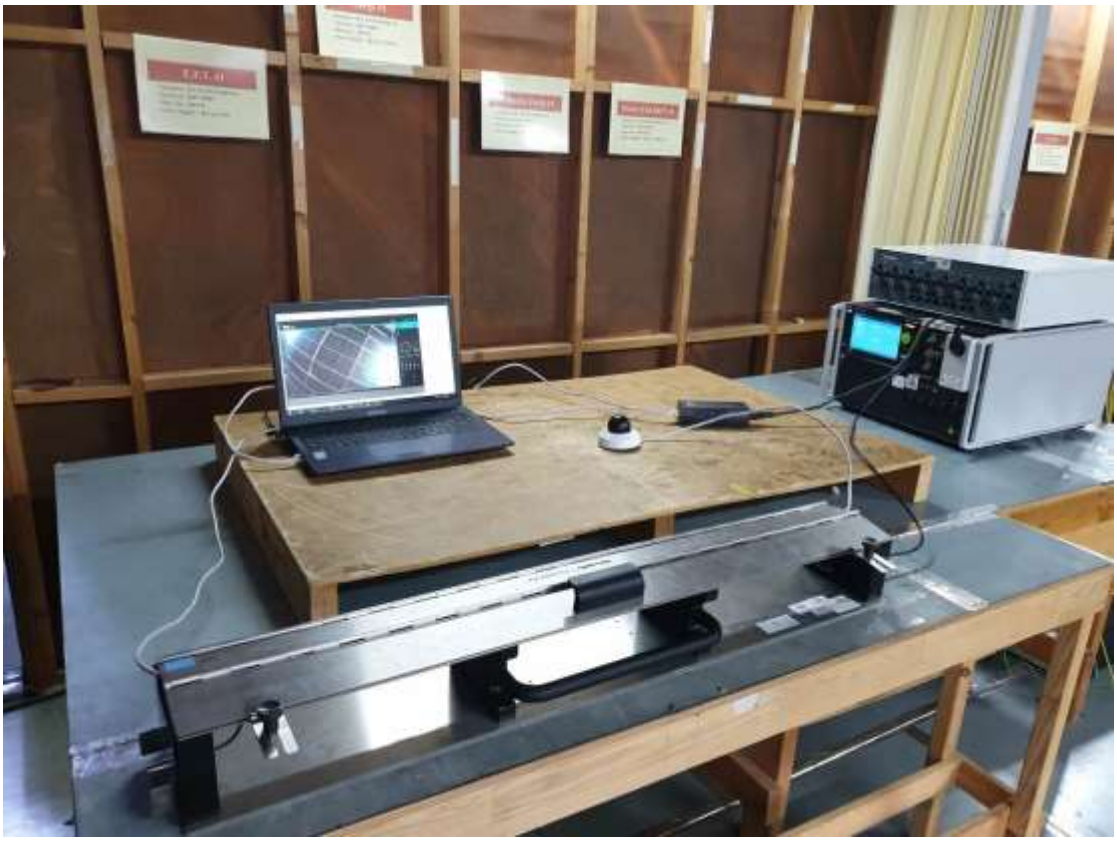




Electrostatic discharge

RF Electromagnetic Field

Electrical fast transients



Conducted Disturbances, Induced by Radio-Frequency Fields

EUT

EUT

EUT